Ullrich Pietsch

List of Publications by Year
in descending order

287	5,323	147801	133252
papers	citations	31 h-index	59 g-index

295	295	295	5559
all docs	docs citations	times ranked	citing authors

#	Article	IF	Citations
1	Effect of Molecular Weight on the Structure and Crystallinity of Poly(3-hexylthiophene). Macromolecules, 2006, 39, 2162-2171.	4.8	385
2	High-Resolution X-Ray Scattering. Advanced Texts in Physics, 2004, , .	0.5	364
3	From anisotropic photo-fluidity towards nanomanipulation in the optical near-field. Nature Materials, 2005, 4, 699-703.	27.5	258
4	Inducing Spin Crossover in Metallo-supramolecular Polyelectrolytes through an Amphiphilic Phase Transition. Journal of the American Chemical Society, 2005, 127, 3110-3114.	13.7	129
5	Thickness Dependence of the Crystalline Structure and Hole Mobility in Thin Films of Low Molecular Weight Poly(3-hexylthiophene). Macromolecules, 2008, 41, 6800-6808.	4.8	114
6	Bimodal Temperature Behavior of Structure and Mobility in High Molecular Weight P3HT Thin Films. Macromolecules, 2009, 42, 4651-4660.	4.8	102
7	Controlled Synthesis of CdSe Nanowires by Solutionâ€“Liquidâ€“Solid Method. Advanced Functional Materials, 2009, 19, 3650-3661.	14.9	90
8	Development of the DEPFET Sensor With Signal Compression: A Large Format X-Ray Imager With Mega-Frame Readout Capability for the European XFEL. IEEE Transactions on Nuclear Science, 2012, 59, 3339-3351.	2.0	83
9	Tuning the Structure and the Magnetic Properties of Metallo-supramolecular Polyelectrolyteâ^'Amphiphile Complexes. Journal of the American Chemical Society, 2011, 133, 547-558.	13.7	78
10	Î²-Carrageenan Enhances the Biomineralization and Osteogenic Differentiation of Electrospun Polyhydroxybutyrate and Polyhydroxybutyrate Valerate Fibers. Biomacromolecules, 2017, 18, 1563-1573.	5.4	68
11	Coplanar and grazing incidence x-ray-diffraction investigation of self-organized SiGe quantum dot multilayers. Physical Review B, 1998, 58, 7934-7943.	3.2	67
12	Impact of Thermal Annealing on the Semicrystalline Nanomorphology of Spin-Coated Thin Films of Regioregular Poly(3-alkylthiophene)s as Observed by High-Resolution Transmission Electron Microscopy and Grazing Incidence X-ray Diffraction. Macromolecules, 2012, 45, 5575-5585.	4.8	66
13	High-Mobility, Ultrathin Organic Semiconducting Films Realized by Surface-Mediated Crystallization. Nano Letters, 2018, 18, 9-14.	9.1	64
14	Depthâ€resolved measurement of lattice relaxation in Ga1â^'xInxAs/GaAs strained layer superlattices by means of grazingâ€incidence xâ€ray diffraction. Journal of Applied Physics, 1993, 74, 2381-2387.	2.5	61
15	Quantitative Analysis of the Electrostatic Potential in Rock-Salt Crystals Using Accurate Electron Diffraction Data. Journal of Physical Chemistry B, 2001, 105, 5068-5074.	2.6	57
16	Liquid Crystalline Phase Transition Induces Spin Crossover in a Polyelectrolyte Amphiphile Complex. Journal of the American Chemical Society, 2009, 131, 2934-2941.	13.7	56
17	Grazing-incidence diffraction from multilayers. Physical Review B, 1995, 51, 16848-16859.	3.2	55
18	Spin-crossover phenomena in extended multi-component metallo-supramolecular assemblies. Coordination Chemistry Reviews, 2009, 253, 2414-2422.	18.8	55

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19	Energy-dispersive X-ray reflectivity and GID for real-time growth studies of pentacene thin films. Thin Solid Films, 2007, 515, 5606-5610.	1.8	53
20	Formation of a Buried Lateral Density Grating in Azobenzene Polymer Films. Advanced Materials, 2000, 12, 1129-1132.	21.0	47
21	Linear viscoelastic analysis of formation and relaxation of azobenzene polymer gratings. Journal of Chemical Physics, 2004, 120, 4039-4045.	3.0	47
22	ADAM, the new reflectometer at the ILL. Physica B: Condensed Matter, 1998, 248, 349-354.	2.7	43
23	Investigation of the compositional depth profile in epitaxial submicrometer layers ofAIIIBVheterostructures. Journal of Applied Crystallography, 1988, 21, 386-392.	4.5	41
24	A dynamical diffraction approach to grazing-incidence X-ray diffraction by multilayers with lateral lattice misfits. Journal Physics D: Applied Physics, 1995, 28, 2522-2528.	2.8	39
25	Simultaneous resonant x-ray diffraction measurement of polarization inversion and lattice strain in polycrystalline ferroelectrics. Scientific Reports, 2016, 6, 20829.	3.3	39
26	Critical Points in a Crystal and Procrystal. Structural Chemistry, 1998, 9, 249-254.	2.0	36
27	Xâ€Ray Bond Charge in GaAs and InSb. Physica Status Solidi (B): Basic Research, 1981, 103, 93-100.	1.5	35
28	Investigations of semiconductor superlattices by depthâ€sensitive xâ€ray methods. Journal of Applied Physics, 1993, 74, 146-152.	2.5	34
29	Application of a pnCCD in X-ray diffraction: a three-dimensional X-ray detector. Journal of Synchrotron Radiation, 2008, 15, 449-457.	2.4	33
30	Strain accommodation in Ga-assisted GaAs nanowires grown on silicon (111). Nanotechnology, 2012, 23, 305703.	2.6	33
31	Enhancement in crystallinity of poly(3â€hexylthiophene) thin films prepared by lowâ€temperature drop casting. Journal of Applied Polymer Science, 2012, 125, 2335-2341.	2.6	33
32	Electrochemical Surface Oxidation of Copper Studied by in Situ Grazing Incidence X-ray Diffraction. Journal of Physical Chemistry C, 2019, 123, 13253-13262.	3.1	32
33	Formation and dynamics of polymer surface relief gratings. Applied Surface Science, 2001, 182, 272-279.	6.1	31
34	Crystallography under External Electric Field. Zeitschrift Fur Anorganische Und Allgemeine Chemie, 2013, 639, 1953-1962.	1.2	31
35	Axial strain in GaAs/InAs core-shell nanowires. Applied Physics Letters, 2013, 102, .	3.3	31
36	The behavior of short fatigue cracks during Very High Cycle (VHCF) Fatigue of duplex stainless steel. Engineering Fracture Mechanics, 2015, 145, 197-209.	4.3	31

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37	Evolution of Polytypism in GaAs Nanowires during Growth Revealed by Time-ResolvedinÂsitux-ray Diffraction. Physical Review Letters, 2015, 114, 055504.	7.8	30
38	Large piezoelectricity in electric-field modified single crystals of SrTiO3. Applied Physics Letters, 2016, 109, .	3.3	30
39	X-ray investigations of the molecular mobility within polymer surface gratings. Journal of Applied Physics, 2000, 87, 7712-7719.	2.5	29
40	Thin Layers of Columns of an Amphiphilic Hexa-peri-hexabenzocoronene at Silicon Wafer Surfaces. Langmuir, 2003, 19, 5036-5041.	3.5	29
41	Structure and Temperature Behavior of Metallo-supramolecular Assemblies. Journal of Physical Chemistry B, 2005, 109, 12795-12799.	2.6	29
42	Time-resolved x-ray diffraction study of the piezoelectric crystal response to a fast change of an applied electric field. Journal of Applied Physics, 2010, 108, 064911.	2.5	29
43	Correlation of Electrical and Structural Properties of Single As-Grown GaAs Nanowires on Si (111) Substrates. Nano Letters, 2015, 15, 981-989.	9.1	29
44	Ultrathin Solid Polyelectrolyteâ^'Surfactant Complex Films:Â Structure and Wettingâ€. Langmuir, 2000, 16, 8562-8567.	3.5	28
45	Energy dispersive x-ray reflectivity technique to study thermal properties of polymer films. Journal of Applied Physics, 2003, 94, 2882-2887.	2.5	28
46	The influence of free carriers on the equilibrium lattice parameter of semiconductor materials. Physica Status Solidi A, 1983, 80, 165-172.	1.7	27
47	Ion-induced nanopatterns on semiconductor surfaces investigated by grazing incidence x-ray scattering techniques. Journal of Physics Condensed Matter, 2009, 21, 224007.	1.8	27
48	In situthree-dimensional reciprocal-space mapping during mechanical deformation. Journal of Synchrotron Radiation, 2012, 19, 688-694.	2.4	27
49	Sub-pixel resolution of a pnCCD for X-ray white beam applications. Journal of Instrumentation, 2013, 8, P05005-P05005.	1.2	27
50	Role of Liquid Indium in the Structural Purity of Wurtzite InAs Nanowires That Grow on Si(111). Nano Letters, 2014, 14, 6878-6883.	9.1	27
51	Individual GaAs nanorods imaged by coherent X-ray diffraction. Journal of Synchrotron Radiation, 2009, 16, 796-802.	2.4	26
52	Quantitative Ultrasonic Characterization of c-Axis Oriented Polycrystalline AlN Thin Film for Smart Device Application. Acta Acustica United With Acustica, 2015, 101, 675-683.	0.8	26
53	Light-induced modifications of Langmuir-Blodgett multilayer assemblies containing amphotropic azocopolymers. Thin Solid Films, 1994, 247, 235-239.	1.8	25
54	Atomic force microscopy inspection of the early state of formation of polymer surface relief gratings. Applied Physics Letters, 2001, 79, 2357-2359.	3.3	25

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55	Investigation of the in-plane structure of Pb and Ni stearate multilayers by means of grazing incidence X-ray diffraction. Thin Solid Films, 1994, 244, 1061-1066.	1.8	24
56	X-ray and neutron diffuse scattering from multilayers of fatty acid salt molecules. Physica B: Condensed Matter, 1996, 221, 284-288.	2.7	23
57	The energy-dispersive reflectometer/diffractometer at BESSY-I. Measurement Science and Technology, 1999, 10, 354-361.	2.6	23
58	Atomistic origin of the inverse piezoelectric effect in Î±-SiO 2 and Î±-GaPO 4. Europhysics Letters, 2003, 62, 834-840.	2.0	23
59	Mechanical characterization of sintered piezo-electric ceramic material using scanning acoustic microscope. Ultrasonics, 2012, 52, 989-995.	3.9	23
60	The multi-purpose hard X-ray beamline BL10 at the DELTA storage ring. Journal of Synchrotron Radiation, 2014, 21, 819-826.	2.4	23
61	The lamellar-columnar transition in Langmuir-Blodgett multilayers of cadmium soaps. Thin Solid Films, 1994, 237, 236-243.	1.8	22
62	Energy-dispersive Laue diffraction by means of a frame-store pnCCD. Journal of Applied Crystallography, 2009, 42, 1139-1146.	4.5	22
63	Structural polytypism and residual strain in GaAs nanowires grown on Si(111) probed by single-nanowire X-ray diffraction. Journal of Applied Crystallography, 2012, 45, 239-244.	4.5	22
64	Multichannel FPGA-Based Data-Acquisition-System for Time-Resolved Synchrotron Radiation Experiments. IEEE Transactions on Nuclear Science, 2017, 64, 1320-1326.	2.0	22
65	Lattice-parameter-difference measurement of heteroepitaxial structures by means of extremely asymmetrical Bragg diffraction. Journal of Applied Crystallography, 1987, 20, 8-10.	4.5	21
66	Investigations of pH-dependent domain structure of lead arachidate Langmuir-Blodgett films by means of x-ray specular and diffuse scattering and atomic force microscopy. Journal of Chemical Physics, 1999, 110, 8104-8111.	3.0	21
67	Xâ€Ray Determination of Bond Charges in Silicon. Physica Status Solidi (B): Basic Research, 1980, 102, 127-133.	1.5	20
68	Coherence phenomena in x-ray diffuse scattering on organic multilayers. Journal Physics D: Applied Physics, 1996, 29, 3161-3165.	2.8	20
69	Lateral arrangement of self-assembled quantum dots in an SiGe/Si superlattice. Journal Physics D: Applied Physics, 1999, 32, A234-A238.	2.8	20
70	X-ray investigations of formation efficiency of buried azobenzene polymer density gratings. Journal of Applied Physics, 2003, 93, 3161-3166.	2.5	20
71	Analysis of VHCF damage in a duplex stainless steel using hard X-ray diffraction techniques. International Journal of Fatigue, 2014, 66, 177-182.	5.7	20
72	Radial Growth of Self-Catalyzed GaAs Nanowires and the Evolution of the Liquid Ga-Droplet Studied by Time-Resolved in Situ X-ray Diffraction. Nano Letters, 2018, 18, 101-108.	9.1	20

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73	Microcrack initiation mechanism of a duplex stainless steel under very high cycle fatigue loading condition: The significance of load partitioning and micro residual stresses. Acta Materialia, 2020, 199, 278-287.	7.9	20
74	Investigation of a semiconductor superlattice by use of grazing incidence X-ray diffraction. Applied Surface Science, 1992, 54, 502-506.	6.1	18
75	Localization of a magnesium .delta.-sheet within a lead stearate Langmuir-Blodgett multilayer by x-ray reflectivity measurement. Langmuir, 1993, 9, 208-210.	3.5	18
76	Structural characterisation of a GaAs surface wire structure by triple axis X-ray grazing incidence diffraction. Physica B: Condensed Matter, 1998, 248, 104-108.	2.7	18
77	Temperature- and time-resolved X-ray scattering at thin organic films. Journal of Synchrotron Radiation, 2002, 9, 206-209.	2.4	18
78	Double pinhole diffraction of white synchrotron radiation. Physica B: Condensed Matter, 2003, 336, 63-67.	2.7	18
79	Analysis of polycrystallinity in hen egg-white lysozyme using a pnCCD. Journal of Applied Crystallography, 2012, 45, 517-522.	4.5	18
80	Influence of alkyl side chain length on the in-plane stacking of room temperature and low temperature cast poly(3-alkylthiophene) thin films. European Polymer Journal, 2015, 67, 199-212.	5.4	18
81	Investigation of Dynamical Bond Charge Transfer in GaAs by Changing X-Ray Reflection Power under High Electric Field. Physica Status Solidi (B): Basic Research, 1985, 131, 67-73.	1.5	17
82	Temperature dependence of the lattice constant in doped and nonstoichiometric GaAs, GaAs1â^'xPx, and GaP. Physica Status Solidi A, 1988, 106, 451-457.	1.7	17
83	The influence of specular interface reflection on grazing incidence X-ray diffraction and diffuse scattering from superlattices. Physica B: Condensed Matter, 1994, 198, 249-252.	2.7	17
84	Xâ€ray supermirrors for BESSY II. Review of Scientific Instruments, 1995, 66, 4845-4846.	1.3	17
85	Evaluation of strain distribution in freestanding and buried lateral nanostructures. Physical Review B, 1999, 60, 16701-16714.	3.2	17
86	Xâ€ray investigation of CdSe nanowires. Physica Status Solidi (A) Applications and Materials Science, 2009, 206, 1752-1756.	1.8	17
87	Time-Resolved X-Ray Diffraction Reveals the Hidden Mechanism of High Piezoelectric Activity in a Uniaxial Ferroelectric. Physical Review Letters, 2015, 114, 097601.	7.8	17
88	Polytypism in GaAs nanowires: determination ofÂthe interplanar spacing of wurtzite GaAs by X-ray diffraction. Journal of Synchrotron Radiation, 2015, 22, 67-75.	2.4	17
89	Impact of the Shadowing Effect on the Crystal Structure of Patterned Self-Catalyzed GaAs Nanowires. Nano Letters, 2019, 19, 4263-4271.	9.1	17
90	Thermally-induced phase transitions in LB multilayers of lead stearate. Thin Solid Films, 1995, 256, 198-204.	1.8	16

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91	Investigation of the chain-chain interface in a lead-stearate multilayer using neutron reflectivity. Thin Solid Films, 1995, 266, 234-237.	1.8	16
92	Comparison of Experimental and Theoretical Structure Amplitudes and Valence Charge Densities of GaAs. Acta Crystallographica Section B: Structural Science, 1998, 54, 231-239.	1.8	16
93	X-ray and Neutron Reflection Analysis of the Structure and the Molecular Exchange Process in Simple and Complex Fatty Acid Salt Langmuirâ^'Blodgett Multilayers. Langmuir, 1999, 15, 1833-1841.	3.5	16
94	Near surface silicide formation after off-normal Fe-implantation of Si(001) surfaces. Journal of Applied Physics, 2014, 116, 024301.	2.5	16
95	Dielectricâ€“Semiconductor Interface Limits Charge Carrier Motion at Elevated Temperatures and Large Carrier Densities in a Highâ€Mobility Organic Semiconductor. Advanced Functional Materials, 2019, 29, 1807867.	14.9	16
96	Extreme asymmetric X-ray Bragg reflection of semiconductor heterostructures near the edge of total external reflection. Journal of Applied Crystallography, 1990, 23, 228-233.	4.5	15
97	A comparison of X-ray methods for structure refinement of Langmuir-Blodgett multilayers. Acta Polymerica, 1992, 43, 206-209.	0.9	15
98	Ab initio Hartreeâ€“Fock study of the electronic charge density of the cubic boron nitride and its comparison with experiments. Acta Crystallographica Section B: Structural Science, 1996, 52, 586-595.	1.8	15
99	Scanning system for high-energy electron diffractometry. Journal of Applied Crystallography, 1999, 32, 1033-1038.	4.5	15
100	Alteration of the mechanical properties of azopolymer film in the process of surface relief grating formation. Applied Physics Letters, 2009, 94, .	3.3	15
101	In situ doping of catalyst-free InAs nanowires with Si: Growth, polytypism, and local vibrational modes of Si. Applied Physics Letters, 2013, 103, .	3.3	15
102	Ferroelectric domain wall dynamics characterized with X-ray photon correlation spectroscopy. Proceedings of the National Academy of Sciences of the United States of America, 2018, 115, E6680-E6689.	7.1	15
103	In-plane strain distribution in free-standing GaAs/InGaAs/GaAs single quantum well surface nanostructures on GaAs[001]. Journal of Applied Physics, 1999, 85, 1524-1530.	2.5	14
104	Evidence of a density grating under light induced formation of surface relief gratings at polymers containing azobenzene moieties. Journal of Applied Physics, 2003, 94, 963-967.	2.5	14
105	Iron self-diffusion in nanocrystalline FeZr thin films. Journal of Non-Crystalline Solids, 2004, 343, 39-47.	3.1	14
106	Significance and Mechanism of the Crack Initiation Process during Very High Cycle Fatigue of Duplex Stainless Steel. Procedia Engineering, 2014, 74, 143-146.	1.2	14
107	Characterization of Ga1â^'xAlxAs/GaAs superlattices and thin single layers by X-ray diffraction. Physica Status Solidi A, 1988, 105, 197-205.	1.7	13
108	A critical review of the experimental valence charge density of GaAs. Acta Crystallographica Section B: Structural Science, 1996, 52, 596-604.	1.8	13

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109	Investigation of the vertical molecular exchange in a complex organic multilayer system. Physica B: Condensed Matter, 1998, 248, 258-262.	2.7	13
110	X-ray study of lateral strain and composition modulation in an AlGaAs overlayer induced by a GaAs lateral surface grating. Journal of Applied Physics, 1998, 84, 1366-1370.	2.5	13
111	A monolithic Fresnel bimirror for hard X-rays and its application for coherence measurements. Journal of Synchrotron Radiation, 2007, 14, 196-203.	2.4	13
112	Grazing Incidence Small Angle X-ray Scattering on Colloidal Crystals. Journal of Physical Chemistry B, 2010, 114, 12473-12479.	2.6	13
113	Single-shot full strain tensor determination with microbeam X-ray Laue diffraction and a two-dimensional energy-dispersive detector. Journal of Applied Crystallography, 2017, 50, 901-908.	4.5	13
114	X-ray diffuse scattering in Langmuir-Blodgett multilayers prepared from fatty acid salts. Journal Physics D: Applied Physics, 1995, 28, A216-A219.	2.8	12
115	Enhancement of field-effect mobility due to structural ordering in poly(3-hexylthiophene) films by the dip-coating technique. Journal of Applied Crystallography, 2013, 46, 908-911.	4.5	12
116	Depth profile investigation of the incorporated iron atoms during Kr+ ion beam sputtering on Si (001). Thin Solid Films, 2013, 527, 349-353.	1.8	12
117	Determination of indium content of GaAs/(In,Ga)As/(GaAs) core-shell(-shell) nanowires by x-ray diffraction and nano x-ray fluorescence. Physical Review Materials, 2018, 2, .	2.4	12
118	Determination of static bond charge properties in Ga_{1â^'x}In_xAs and GaAs_{1â^'y}P_y, solid solutions. Physica Status Solidi (B): Basic Research, 1981, 107, 185-194.	1.5	11
119	Xâ€Ray Electron Charge Density Distribution in Silicon. Physica Status Solidi (B): Basic Research, 1986, 137, 441-447.	1.5	11
120	Xâ€Ray Electron Density Distribution of GaAs. Physica Status Solidi (B): Basic Research, 1986, 138, 47-52.	1.5	11
121	Characterization of InxGa1â^'xAs single quantum wells, buried in GaAs[001], by grazing incidence diffraction. Journal of Applied Physics, 1997, 81, 2601-2606.	2.5	11
122	Grazing incidence diffraction by epitaxial multilayered gratings. Physica B: Condensed Matter, 1998, 248, 343-348.	2.7	11
123	In-plane strain and strain relaxation in laterally patterned periodic arrays of Si/SiGe quantum wires and dot arrays. Applied Physics Letters, 1998, 73, 806-808.	3.3	11
124	Strain investigation of low strained buried gratings by grazing incidence X-ray diffraction and elasticity theory. Europhysics Letters, 1999, 46, 479-485.	2.0	11
125	Electric field induced charge density variations in partially-ionic compounds. Journal of Physics and Chemistry of Solids, 2001, 62, 2129-2133.	4.0	11
126	White beam x-ray waveguide optics. Applied Physics Letters, 2004, 85, 161-163.	3.3	11

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127	Coherence experiments using white synchrotron radiation. Physica B: Condensed Matter, 2005, 357, 45-52.	2.7	11
128	Timeâ€“space transformation of femtosecond free-electron laser pulses by periodical multilayers. Journal of Synchrotron Radiation, 2008, 15, 19-25.	2.4	11
129	Nanocrystalline iron nitride films with perpendicular magnetic anisotropy. Applied Physics Letters, 2008, 92, 052504.	3.3	11
130	Direct Correlation Between Electric and Structural Properties During Solidification of Poly(3â€hexylthiophene) Dropâ€Cast Films. Macromolecular Rapid Communications, 2012, 33, 1765-1769.	3.9	11
131	A new method for polychromatic X-ray Î¼Laue diffraction on a Cu pillar using an energy-dispersive pn-junction charge-coupled device. Review of Scientific Instruments, 2014, 85, 113901.	1.3	11
132	Local Orientational Structure of a P3HT Ï€â€“Ï€ Conjugated Network Investigated by X-ray Nanodiffraction. Journal of Physical Chemistry Letters, 2014, 5, 2335-2339.	4.6	11
133	Combining high time and angular resolutions: time-resolved X-ray powder diffraction using a multi-channel analyser detector. Journal of Applied Crystallography, 2015, 48, 970-974.	4.5	11
134	Threefold rotational symmetry in hexagonally shaped coreâ€“shell (In,Ga)As/GaAs nanowires revealed by coherent X-ray diffraction imaging. Journal of Applied Crystallography, 2017, 50, 673-680.	4.5	11
135	Complete structural and strain analysis of single GaAs/(In,Ga)As/GaAs coreâ€“shellâ€“shell nanowires by means of in-plane and out-of-plane X-ray nanodiffraction. Journal of Applied Crystallography, 2018, 51, 1387-1395.	4.5	11
136	Correlated Nanoscale Analysis of the Emission from Wurtzite versus Zincblende (In,Ga)As/GaAs Nanowire Coreâ€“Shell Quantum Wells. Nano Letters, 2019, 19, 4448-4457.	9.1	11
137	Static and Dynamical Valence Charge and Bond Charge Properties of Zincblende Structure Compounds. Physica Status Solidi (B): Basic Research, 1985, 128, 439-451.	1.5	10
138	Differential-mode grazing-incidence diffraction from nanometre-layer heterostructures. Semiconductor Science and Technology, 1991, 6, 743-747.	2.0	10
139	X-ray diffuse scattering from lead stearate multilayers. Thin Solid Films, 1994, 247, 230-234.	1.8	10
140	Identification of a buried single quantum well within surface structured semiconductors using depth resolved x-ray grazing incidence diffraction. Journal Physics D: Applied Physics, 1997, 30, L55-L59.	2.8	10
141	Electric-fieldâ€“induced electron density response of GaAs and ZnSe. Europhysics Letters, 1998, 44, 714-720.	2.0	10
142	Strain relaxation in periodic arrays of Si/SiGe quantum wires determined by coplanar high-resolution x-ray diffraction and grazing incidence diffraction. Journal Physics D: Applied Physics, 1999, 32, A224-A229.	2.8	10
143	X-ray Reflectivity Study of an Amphiphilic Hexa-peri-hexabenzocoronene at a Structured Silicon Wafer Surface. Langmuir, 2003, 19, 10997-10999.	3.5	10
144	X-ray investigation of the interface structure of free standing InAs nanowires grown on GaAs $[ar{1}ar{1}ar{1}]_{mathrm{B}}$. Applied Physics A: Materials Science and Processing, 2009, 96, 851-859.	2.3	10

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145	Xe ion beam induced rippled structures on differently oriented single-crystalline Si surfaces. Journal Physics D: Applied Physics, 2010, 43, 112001.	2.8	10
146	Structural and morphological changes of P3HT films in the planar geometry of an OFET device under an applied electric field. European Polymer Journal, 2011, 47, 2189-2196.	5.4	10
147	Strain relaxation and ambipolar electrical transport in GaAs/InSb coreâ€“shell nanowires. Nanoscale, 2017, 9, 18392-18401.	5.6	10
148	Local scale structural changes of working OFET devices. Nanoscale, 2020, 12, 2434-2438.	5.6	10
149	Characterization of lateral semiconductor nanostructures by means of x-ray grazing-incidence diffraction. Applied Physics Letters, 1997, 70, 1031-1033.	3.3	9
150	Grazing-incidence diffraction strain analysis of a laterally-modulated multiquantum well system produced by focused-ion-beam implantation. Applied Physics Letters, 2000, 77, 4277-4279.	3.3	9
151	X-ray reflectivity analysis of thin complex Langmuir-Blodgett films. Journal Physics D: Applied Physics, 2001, 34, 450-458.	2.8	9
152	Investigation of azobenzene side group orientation in polymer surface relief gratings by means of photoelectron spectroscopy. Applied Physics Letters, 2004, 84, 1561-1563.	3.3	9
153	Microstructural anisotropy at the ion-induced rippled amorphous-crystalline interface of silicon. Applied Physics Letters, 2006, 89, 231915.	3.3	9
154	Grazing-incidence X-ray diffraction of single GaAs nanowires at locations defined by focused ion beams. Journal of Applied Crystallography, 2013, 46, 887-892.	4.5	9
155	Experimental investigation and numerical description of the damage evolution in a duplex stainless steel subjected to VHCF-loading. Materials Science & Engineering A: Structural Materials: Properties, Microstructure and Processing, 2015, 646, 8-18.	5.6	9
156	A microcontroller for in situ single-crystal diffraction measurements with a PILATUS-2M detector under an alternating electric field. Journal of Applied Crystallography, 2017, 50, 975-977.	4.5	9
157	Characterization of individual stacking faults in aÂwurtzite GaAs nanowire by nanobeam X-ray diffraction. Journal of Synchrotron Radiation, 2017, 24, 981-990.	2.4	9
158	Temperature Dependence of Bond charge Vibration in Silicon. Physica Status Solidi (B): Basic Research, 1980, 102, 503-508.	1.5	8
159	Simulation fo Dynamical Bond Charge Transfer Properties in Elemental Semiconductors by Means of a Simple Quantumâ€Mechanical Model. Physica Status Solidi (B): Basic Research, 1984, 126, 595-605.	1.5	8
160	Investigation of (Ga,In)(As,P)/InP single heterostructures by means of extremely asymmetrical Bragg diffraction using synchrotron radiation. Journal of Applied Crystallography, 1988, 21, 240-244.	4.5	8
161	Depth resolved investigation of the relaxation behaviour in strained GaInAs/GaAs superlattices. Physica B: Condensed Matter, 1994, 198, 256-258.	2.7	8
162	Structure of thermally treated oxadiazoleamide Langmuir-Blodgett films. Supramolecular Science, 1997, 4, 455-459.	0.7	8

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163	Analysis of the strain distribution in lateral nanostructures for interpreting photoluminescence data. Physica B: Condensed Matter, 2000, 283, 92-96.	2.7	8
164	Multipole analysis of the electron density and electrostatic potential in germanium by high-resolution electron diffraction. Journal of Physics and Chemistry of Solids, 2001, 62, 2135-2142.	4.0	8
165	In situx-ray reflectivity and grazing incidence x-ray diffraction study ofL10ordering in57Fe/Pt multilayers. Journal of Physics Condensed Matter, 2009, 21, 186002.	1.8	8
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